Reliability in the Age of Big Data

TNO - Jan Eite Bullema | ASQ CQE, ASQ CSSBB

29 NOVEMBER 2018 TECHNIEKHUYS VELDHOVEN

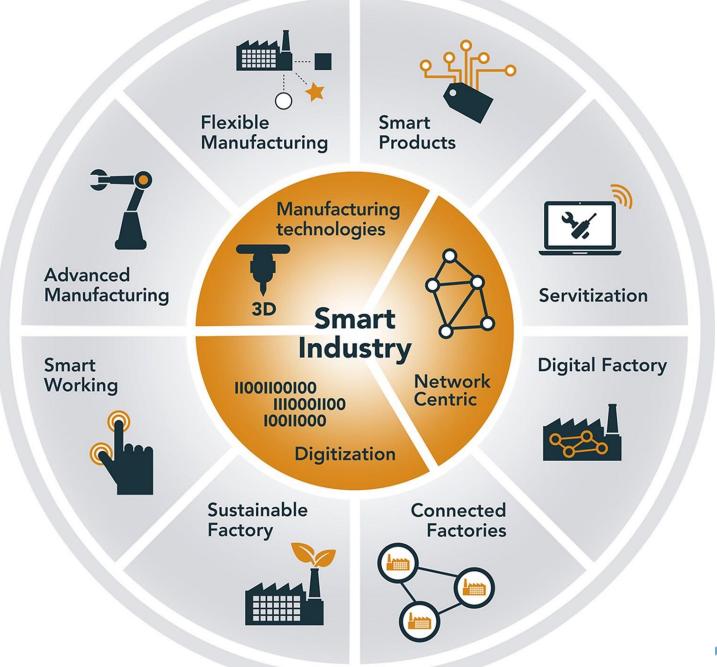
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Reliability in the Age of Big DATA

The nature of Big Data: **new types of data** Opportunities of Big Data for Reliability: **new reliability methods** *New degradation models and application of Digital Twins New types of covariates Application of Machine Learning* Emergence of **new reliability applications** *New propositions: use based insurance, early warning warranty*



The nature of Big Data: Many V's

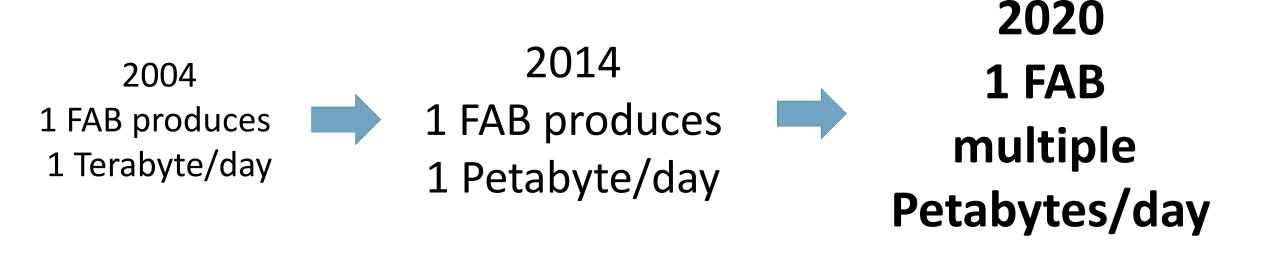
Many V's (Variety, Volume, Veracity, Velocity, Value, Variability, Visualise) brontobyte (10^{27}) = 1000 yottabyte (10^{24}) = 1000000 zettabyte (10^{21})

Big Data has often complex structures or is even totally unstructured high speed sensor data, video, images, text, weather, environment, Email

Emergence of (Industrial) Internet of Things 2015: 15 billion iot sensors/devices 2025: 75 billion iot sensors/devices



Big data in Semicon Manufacturing Explosion in Generated Data



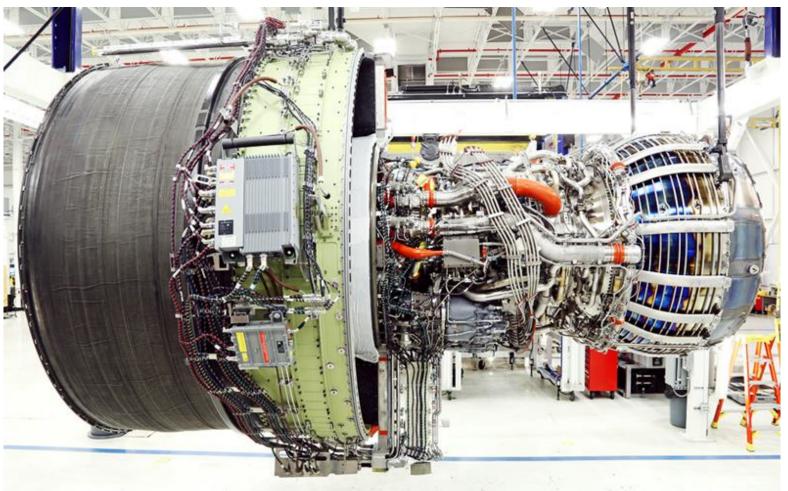


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http://electroiq.com/blog/2014/09/the-semiconductor-industry-out-in-front-but-lagging-behind

Twin-engine aircraft with 12-hr. flighttime can produce up to 844 TB of data



TNO innovation for life

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http://aviationweek.com/connected-aerospace/internet-aircraft-things-industry-set-be-transformed



Value Creation in Industry 4.0

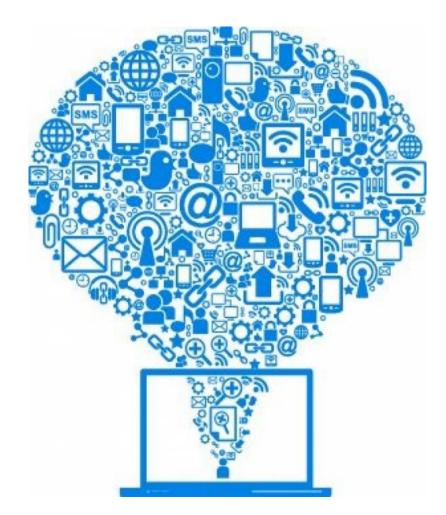


Most value creation in implementation of Industry 4.0 will occur not by replacing equipment as in previous industrial revolutions, but by equipping existing equipment with sensors so that machines can be used more efficiently and productively





The nature of Big Data: new data types



Multi variate time series date: e.g. high speed multi-channel sensor data

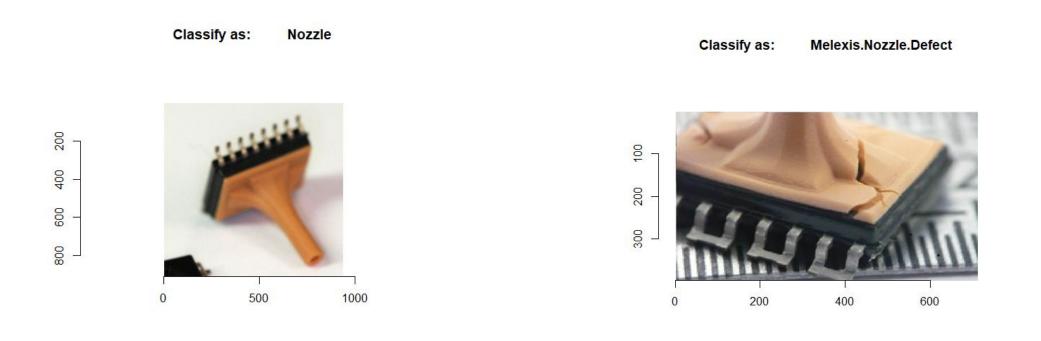
Functional Data: *e.g. functional curves, e.g. data from spectrometers*

Image Data / Video Streams: *e.g. camera image data or electron microscope image data*

Unstructured: e.g. text, audio



Example of New Data Types: images al THE PROVENENT OF New Data Types: images al THE PROVENENT OF NEW PROVENCE O





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set up the deep learning model

data <- mx.symbol.Variable("data")</pre>

model <- mx.model.FeedForward.create(softmax,</pre>

print(proc.time() - tic)

dim(preds) #preds

preds <- predict(model, test.x)</pre>

pred.label <- max.col(t(preds)) - 1</pre>

Classify as:

500

fc1 <- mx.symbol.FullyConnected(data, name="fc1", num hidden=250) act1 <- mx.symbol.Activation(fc1, name="relu1", act type="relu") fc2 <- mx.symbol.FullyConnected(act1, name="fc2", num hidden=500) act2 <- mx.symbol.Activation(fc2, name="relu2", act type="relu") fc3 <- mx.symbol.FullyConnected(act2, name="fc3", num hidden=1000) act3 <- mx.symbol.Activation(fc3, name="relu3", act type="relu") fc4 <- mx.symbol.FullyConnected(act3, name="fc4", num hidden=500) act4 <- mx.symbol.Activation(fc4, name="relu4", act type="relu") fc5 <- mx.symbol.FullyConnected(act4, name="fc5", num hidden=25) softmax <- mx.symbol.SoftmaxOutput(fc5, name="sm")</pre>

> X=train.x, y=train.y,

momentum=0.9,

N

ctx=devices, num.round=rounds,

eval.metric=mx.metric.accuracy, initializer=mx.init.uniform(0.1),

array.batch.size=125, learning.rate=0.01,

elexis.Nozzle.Defect

Deep Learning Model

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https://aws.amazon.com/mxnet/

200

400

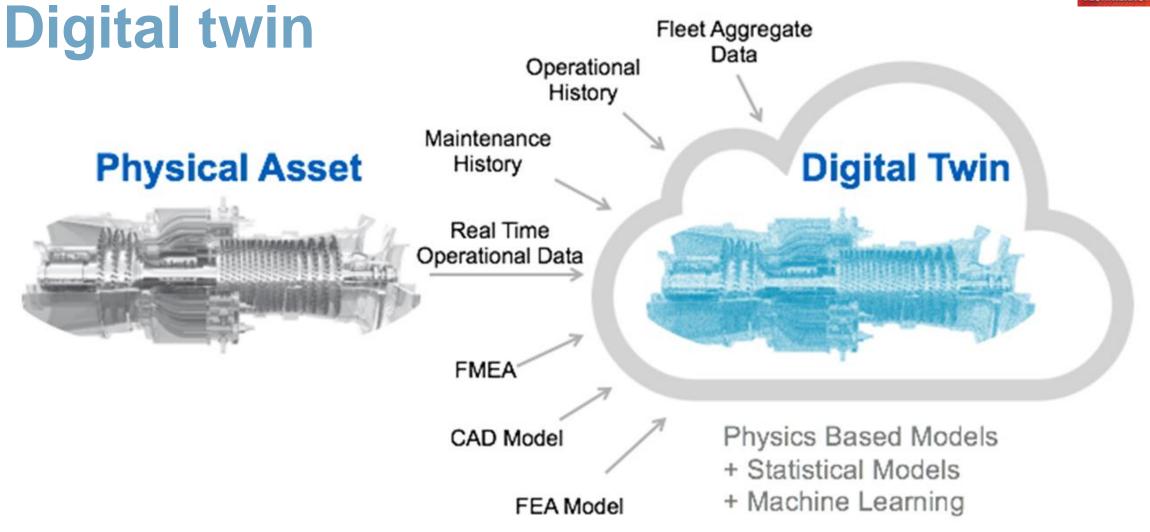
600

800



Example of New Data Types Text Mining misalignment variation stopped Co mixing tailing recoat inspection loose local drop width bubble short speed air stage screw hay effect stop height auger quality. via variations open curing low positio print xyz Grack nok voltage design environmental 2 e detection interna dis continued gove electrical dimensions conductivity dependence

TNO innovation for life



for life

https://www.capgemini.com/2018/08/digital-twin-physical-meets-digital-world/

Digital twin

Model

Complex

Multi-scale

Multi-physics

Modelling

Data Poor

Big Data

Data Rich

Connect and transition to Teo Data modelling

Data Based Techniques / Data Analytics

Life Cycle conception prototype deployment evolution maintenance disposal

Upscaling

Reduced-

order

Modelling



innovation for life





Case: Deposition Tool

Applied Materials claims that a customer increased profits > \$100,000 per chamber, per year using predictive maintenance modelling



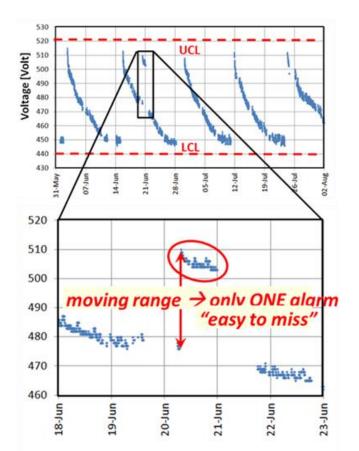






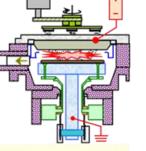
Jan Eite Bullema, How to make Big Data Productive in Semiconductor Manufacturing, 2016





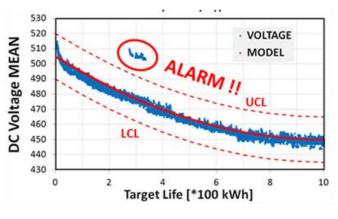
Incident 2004

- "electrical short" Alu heater
- "grounded" i.s.o. "floating"
- metal +10% too thick
- 311 wfrs affected



"narrow" control range around expected value

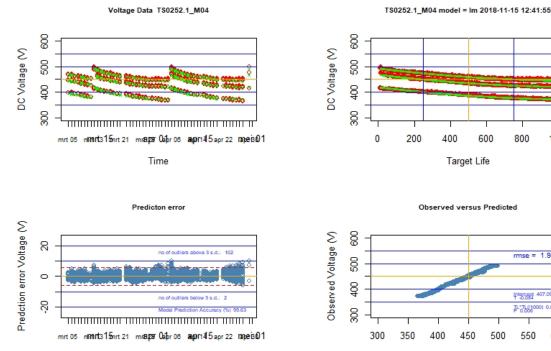
VISION for TOOL CONTROL



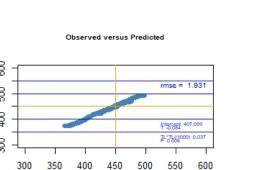
After a serious manufacturing Issue, control charts for deposition were adapted with a general model for sputtering Voltage







Time



800

1000

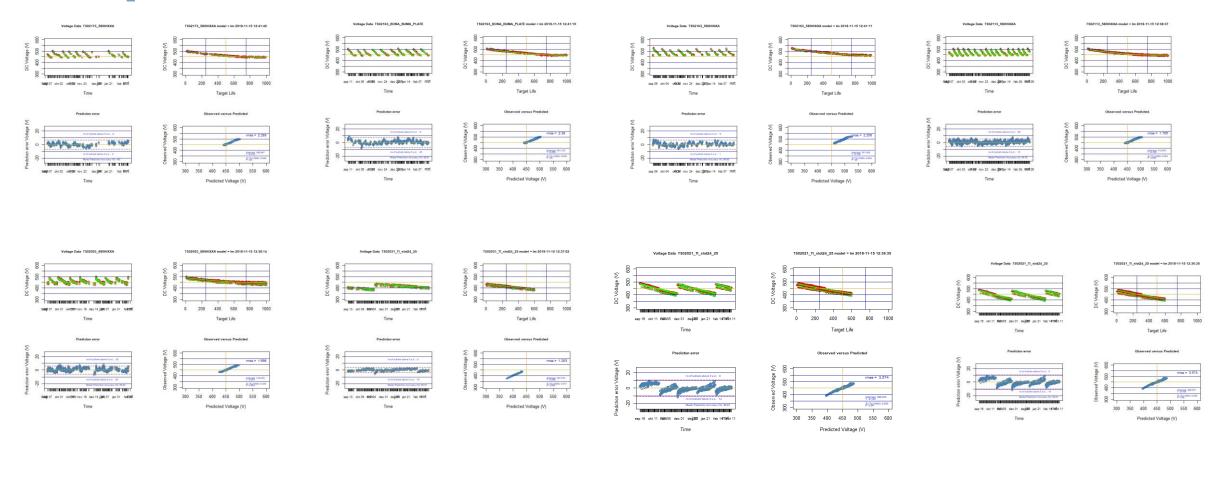
Predicted Voltage (V)

A new model was developed that predicts sputtering Voltage for 18 machines and 40 recipes

This model is 6 times better than the previous Voltage prediction model

The model gives additional information about machine status







Jan Eite Bullema, How to make Big Data Productive in Semiconductor Manufacturing, 2016

CONCLUSION

Big Data technology leads to new types of data high dimensional sensor data, images, functional curves, text messages

That lead to new statistical methods in reliability *functional data analysis, text mining, deep learning and image regression*

That lead to higher levels of reliability and new propositions use based insurance, use based warranty

Thank You for your Attention

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